Notice of References Cited

Application/Control No.	Applicant(s)/Pater	nt Under
10/736,983	Reexamination TOMOYASU ET	AL.
Examiner	Art Unit	
OLVIN LOPEZ	2121	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,514,667	02-2003	Angelopoulos et al.	430/271.1
*	В	US-7,337,019	02-2008	Reiss et al.	700/21
*	С	US-6,665,575	12-2003	Betawar et al.	700/121
*	D	US-7,328,418	02-2008	Yamashita et al.	716/10
*	Е	US-6,864,041	03-2005	Brown et al.	430/316
	F	US-			
	G	US-		-	
	Н	US-			
	Т	US-			
	J	US-			
	к	US-			
	٦	US-			
	м	US-			

FOREIGN PATENT DOCUMENTS

				FOREIGN FATENT DOC	UMENTS	
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q		1			
	R					
	s					
	т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	_	induce de approduce. Pauloi, Ties Date, Paulistiel, Editori di Volulle, Petalielle Pages)
	U	Natzle et al, "Trimming of Hard Masks by COR for gate length control and fr embedded logic", pages 1-5, may 2004.
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A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.